Search Notes

Application/Control	No.

Applicant(s)/Patent under Reexamination

10/690,463

Examiner

CHENG, JYH-NAN
Art Unit

TAN N. TRAN

2826

SEARCHED				
Class	Subclass	Date	Examiner	
257	173	05/05	1	
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
257	173	05/05	T	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
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